CLAIMS

1. A semiconductor device module structure comprising:

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- a high-resistance layer of a first conductive type;
- a base layer of a second conductive type formed in an upper part of the high-resistance layer of the first conductive type;
 - an emitter region of a first conductive type formed in an upper part of the base layer of the second conductive type;
 - an emitter electrode connected to the emitter region;
- an insulated gate electrode adjacent to the base layer of the second conductive type;
 - a guard ring part where diffusion around a cell region including the emitter region has been made deep;
 - a passivation layer formed on the upper part of the guard ring part and not extending onto the upper part of the cell region;
 - a collector layer of the second conductive type formed on the underside of a buffer layer of the first conductive type;
 - a collector electrode connected to the collector layer; and
- a metal flat plate upper heat-sinking part connected to the emitter electrode at a height such that it is non-contacting with the passivation film.
 - 2. The semiconductor device module structure of claim 1, characterized in that the module structure of a semiconductor device further comprises a diode part, and a cathode electrode at an upper part of the diode part and the upper heat-sinking part are connected.